IAP9 Rec'd PCT/PT0=15 DE0-2009

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						Based on PCT/JP04/08454	
LIST OF	BEEE	SENCES CITED BY A	PLICANT	APPLICANT T-MANUAL CATO AA AL			
LIST OF REFERENCES CITED BY APPLICANT				Takuya SATO, et al.		T	
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U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB FILING DATE CLASS IF APPROPRIATE	
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FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY		YES	TRANSLATION NO
/JNY/	AO	1 168 657	01/02/02	EP (equivalent of US 2002-0012383)			NO
	AP	0 847 147	06/10/98	EP (equivalent of US 2001-0012276)		,	NO
	AQ	2002-051007	02/15/02	JP (with English abstract)			. NO
	AR	2003-018090	01/17/03	JP (with English abstract)			NO
	AS	2003-078484	03/14/03	JP (with English abstract)		<u> </u>	NO
	AT	08-125604	05/17/96	JP (with English abstract)			NO
/JNY/	AU	2002-016545	01/18/02	JP (with English abstract)		ļ	NO
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OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
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Examiner	Examiner /Janelle N. Young/ (04/28/2007)  Date Considered 04/28/200						04/28/2007
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